

RADIATED EMISSIONS

DATA

FOR

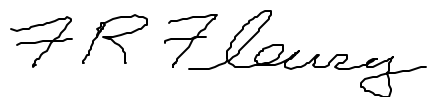
**QUALCOMM, INC.
10300 Campus Point Drive
San Diego, CA 92121**

Prepared by

**TÜV PRODUCT SERVICE
10040 Mesa Rim Road
San Diego, CA 92121-2912**

Measurement Requirements (CFR 47 Part 25, Paragraph 25.202)

The measurements which follow were performed by TÜV Product Service. To the best of my knowledge these tests were conducted in accordance with the procedures outlined in Part 2 of the Commission's Rules and Regulations. The data presented below demonstrates compliance with the appropriate technical standards.

A handwritten signature in cursive script that reads 'F R Fleury'.

Floyd R. Fleury
EMC Manager

Emissions Test Conditions: SPURIOUS RADIATED EMISSIONS

Roof (small open area test site)

The <i>Spurious Radiated Emissions</i> measurements were performed using the following equipment:

Test Equipment Used :

Model No.	Prop. No.	Description	Manufacturer	Serial No.	Cal Due Date
HP8566B	407	Spectrum Analyzer	Hewlett Packard	2311A02209	02/02
HP8445B	809	Automatic Preselector	Hewlett Packard	1442A01127	N/A*
AMF-3D-010180-35-10P	752	Amplifier 20 dB	Miteq	614344	N/A*
FF6548-2	781	2000 MHz High Pass Filter	Sage Laboratories	004	N/A*
3115	251	Double Ridge Antenna	EMCO	2495	10/01
AA-190-30.00.0	732	30 foot HFreq. Cable (1 - 18 GHz)	United Microwave Pro	--	N/A*
AA-190-06.00.0	657	High Freq. Cable	United Microwave Pro	--	N/A*

Remarks: (*) Verified

FCC Part 25, Paragraph 25.202

Globalstar ODU and Globalstar AFUT

Low, mid and high channels tested. All emissions (spurious and harmonics) were greater than 20 dB below the limit. Frequency range investigated from lowest RF frequency generated up to the 10th harmonic.

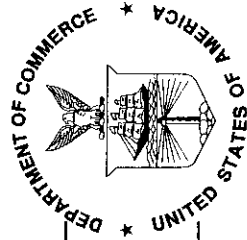
Operating Mode: Transmit Full Power

RBW and VBW = 1 MHz for peak for fundamental and harmonics.

RBW and VBW = 30 kHz 20 video samples for average for fundamental.

Testing Facilities
Certificates of Approval

United States Department of Commerce
National Institute of Standards and Technology



ISO/IEC GUIDE 25:1990
ISO 9002:1987

Certificate of Accreditation

TUV PRODUCT SERVICE, INC.
SAN DIEGO, CA

is recognized under the National Voluntary Laboratory Accreditation Program for satisfactory compliance with criteria established in Title 15, Part 285 Code of Federal Regulations. These criteria encompass the requirements of ISO/IEC Guide 25 and the relevant requirements of ISO 9002 (ANSI/ASQC Q92-1987) as suppliers of calibration or test results. Accreditation is awarded for specific services, listed on the Scope of Accreditation for:

ELECTROMAGNETIC COMPATIBILITY AND TELECOMMUNICATIONS

December 31, 2001

Effective through

David E. Alderman

For the National Institute of Standards and Technology

NVLAP Lab Code: 100268-0

NVLAP-01C (11-96)



ISO/IEC GUIDE 25:1990
ISO 9002:1987

Scope of Accreditation



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**ELECTROMAGNETIC COMPATIBILITY
AND TELECOMMUNICATIONS**

NVLAP LAB CODE 100268-0

TUV PRODUCT SERVICE, INC.

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URL: <http://www.tuvps.com>

NVLAP Code Designation / Description

Emissions Test Methods:


- 12/CIS22 IEC/CISPR 22:1993: Limits and methods of measurement of radio disturbance characteristics of information technology equipment
- 12/CIS22a IEC/CISPR 22:1993: Limits and methods of measurement of radio disturbance characteristics of information technology equipment, Amendment 1:1995, and Amendment 2:1996.
- 12/CIS22b CNS 13438:1997: Limits and Methods of Measurement of Radio Interference Characteristics of Information Technology Equipment
- 12/F01 FCC Method - 47 CFR Part 15 - Digital Devices
- 12/F01a Conducted Emissions, Power Lines, 450 KHz to 30 MHz
- 12/F01b Radiated Emissions

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ELECTROMAGNETIC COMPATIBILITY AND TELECOMMUNICATIONS

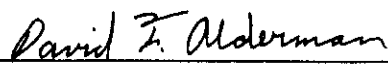
TUV PRODUCT SERVICE, INC.

<i>NVLAP Code</i>	<i>Designation / Description</i>
12/T51	AS/NZS 3548: Electromagnetic Interference - Limits and Methods of Measurement of Information Technology Equipment
MIL-STD-462 : Conducted Emissions:	
12/A01	MIL-STD-462 Method CE01
12/A04	MIL-STD-462 Method CE02
12/A06	MIL-STD-462 Method CE03
12/A08	MIL-STD-462 Method CE04
12/A10	MIL-STD-462 Method CE06
12/A12	MIL-STD-462 Method CE07
MIL-STD-462 : Conducted Susceptibility:	
12/B01	MIL-STD-462 Method CS01
12/B02	MIL-STD-462 Method CS02
12/B04	MIL-STD-462 Method CS03/CS04/CS05/CS08
12/B05	MIL-STD-462 Method CS06

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NVLAP-01S (11-95)



ISO/IEC GUIDE 25:1990
ISO 9002:1987

Scope of Accreditation



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**ELECTROMAGNETIC COMPATIBILITY
AND TELECOMMUNICATIONS**

NVLAP LAB CODE 100268-0

TUV PRODUCT SERVICE, INC.

NVLAP Code Designation / Description

- 12/B06 MIL-STD-462 Method CS07
- 12/B07 MIL-STD-462 Method CS09

MIL-STD-462 : Radiated Emissions:

- 12/D01 MIL-STD-462 Method RE01
- 12/D02 MIL-STD-462 Method RE02
- 12/D03 MIL-STD-462 Method RE03

MIL-STD-462 : Radiated Susceptibility:

- 12/E01 MIL-STD-462 Method RS01
- 12/E02 MIL-STD-462 Method RS02
- 12/E03 MIL-STD-462 Method RS03 (Consult laboratory for field strengths available)
- 12/E04 MIL-STD-462 Method RS03 employing RADHAZ procedures for high level testing
(Consult laboratory for field strengths available)

December 31, 2001

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For the National Institute of Standards and Technology

NVLAP-01S (11-95)

Exhibit 14 Frequency Stability

The test results reported in the following 2 tables are abstracted from the conducted design verification test (DVT) results on 8 sample DVT RAU RF Boards as will be reported in the in-progress Fixed Phone RF Board Design Verification Test Plan, 80-98415-1 X3.

Table 1 presents the mean values of measured frequency variation in parts per million (ppm) at cold (-30° C), ambient, and hot (60° C) temperatures. Table 2 presents the minimum, maximum, and mean values over all temperatures for the 7 boards tested.

Test Equipment

Equipment	Serial Number	Cal Date	Cal Due
Leader DC Power Supply	DE14268	September 14, 2000	September 14, 2001
HP 8593EM Spectrum Analyzer	3412A00107	February 1, 2001	February 12, 2002

Table 1. Mean Variation in TX Frequency with Temperature

	-30 C	Ambient	60 C	Spec.	Delta	
					Amb. To Cold	Amb. To Hot
TX ppm	1.18	0.31	0.36	5.00	0.87	0.04

Table 2. Variation Range for TX Frequency over Temperature Range

	Data for Hot, Cold, Ambient			Test Limit	Std. Dev.	Design Cpk
	Min.	Max.	Mean			
TX ppm	-0.49	2.30	0.65	5.00	0.78	1.9

Statistical Manufacturing Margin

$Cpk = (Average - spec. Limit) / 3 * \text{Sigma Value}$